



American Association for Laboratory Accreditation

Accredited Laboratory

A2LA has accredited

EVANS ANALYTICAL GROUP

East Windsor, NJ

for technical competence in the field of

Chemical Testing

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 *General Requirements for the Competence of Testing and Calibration Laboratories*. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated 8 January 2009).

Presented this 1st day of May 2013.



A handwritten signature in black ink, reading "Peter Abney".

President & CEO
For the Accreditation Council
Certificate Number 2797.05
Valid to August 31, 2015

For the tests or types of tests to which this accreditation applies, please refer to the laboratory's Chemical Scope of Accreditation.



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

EVANS ANALYTICAL GROUP
104 Windsor Center Drive, Suite 101
East Windsor, NJ 08520
Dr. Patrick Schnabel Phone: 408 530 3786

CHEMICAL

Valid To: August 31, 2015

Certificate Number: 2797.05

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform analytical testing including contamination analysis, surface analysis and bulk compositional analysis on: semiconductors, integrated circuits, communication and storage devices, photovoltaic materials, optical components, thin film products, biomedical materials and products, pharmaceutical products, packaging materials, metals, alloys, plastics, polymers, glasses, powders and nanomaterials.

<u>Test</u>	<u>Test Method(s)¹</u>
Secondary Ion Mass Spectrometry (SIMS)	ISO 17560, 14237, 18114 (SOP 8/F1); SEMI MF1617 (F6)
X-Ray Photoelectron Spectroscopy (XPS)	SOP 11/F1
Auger Electron Spectroscopy (AES)	SOP 1/F1; ISO 21270; ASTM E827
Time-of-Flight Secondary Ion Mass Spectrometry (TOF-SIMS)	SOP 9/F1
Scanning Electron Microscopy / Energy Dispersive X-Ray Spectroscopy (SEM/EDS)	SOP 6/F1; ASTM E766, E1508 (qualitative only)
Atomic Force Microscopy (AFM)	SOP 2/F1

¹ Failure analyses performed using test methods listed.